TOSHIBA Transistor Silicon PNP Epitaxial Type

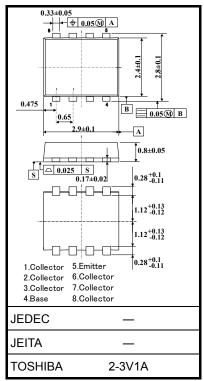
# **TPCP8602**

High-Speed Switching Applications DC-DC Converter Applications Strobe Flash Applications

- High DC current gain:  $h_{FE} = 200$  to 500 (IC = -0.3 A)
- Low collector-emitter saturation:  $V_{CE}$  (sat) = -0.2 V (max)
- High-speed switching: tf = 90 ns (typ.)

#### Absolute Maximum Ratings (Ta = 25°C)

Characteristic		Symbol	Rating	Unit	
Collector-base voltage		V <sub>CBO</sub>	-50	V	
Collector-emitter voltage		V <sub>CEO</sub>	-50	V	
Emitter-base voltage		V <sub>EBO</sub>	-7	V	
Collector current	DC (Note 1)	Ι <sub>C</sub>	-2.5	A	
	Pulse (Note 1)	I <sub>CP</sub>	-4.0		
Base current		Ι <sub>Β</sub>	-0.25	А	
Collector power dissipation (t = 10s)	t = 10s	D <sub>-</sub> (Note 2)	3.0	W	
	DC	P <sub>C</sub> (Note 2)	1.25		
Junction temperature		Tj	150	°C	
Storage temperature range		T <sub>stg</sub>	–55 to 150	°C	



Weight: 0.017 g (typ.)

Note 1: Ensure that the junction temperature does not exceed 150°C during use of this device.

Note 2: Mounted on an FR4 board (glass epoxy, 1.6 mm thick, Cu area: 645 mm<sup>2</sup>)

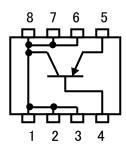
Note 3: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Unit: mm

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## Figure 1. Circuit Configuration (top view)



Note 4: • on the lower left of the marking indicates Pin 1

\* Weekly code (three digits):



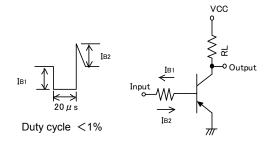
Week of manufacture (01 for the first week of the year, continuing up to 52 or 53) Year of manufacture

(lowest-order digit of the calendar year)

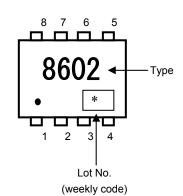
#### **Electrical Characteristics (Ta = 25°C)**

Characteristic		Symbol	Test Condition	Min	Тур.	Max	Unit
Collector cut-off current		I <sub>CBO</sub>	$V_{CB} = -50 \text{ V}, \text{ I}_{E} = 0$	_		-100	nA
Emitter cut-off current		I <sub>EBO</sub>	$V_{EB} = -7 V, I_C = 0$	_		-100	nA
Collector-emitter breakdown voltage		V (BR) CEO	$I_C = -10$ mA, $I_B = 0$	-50	_	—	V
DC current gain		h <sub>FE</sub> (1)	$V_{CE} = -2 \text{ V}, \text{ I}_{C} = -0.3 \text{ A}$	200		500	
		h <sub>FE</sub> (2)	$V_{CE} = -2 \text{ V}, \text{ I}_{C} = -1.0 \text{ A}$	100	_	_	
Collector-emitter saturation voltage		V <sub>CE (sat)</sub>	I <sub>C</sub> = -1 A, I <sub>B</sub> = -33 mA	_		-0.2	V
Base-emitter saturation voltage		V <sub>BE (sat)</sub>	I <sub>C</sub> = -1 A, I <sub>B</sub> = -33 mA	_		-1.1	V
Collector output capacitance		C <sub>ob</sub>	$V_{CB} = 10 \text{ V}, I_E = 0, f = 1 \text{MHz}$	_	20	_	pF
Switching time	Rise time	tr	See Figure 3 circuit diagram $V_{CC} \simeq 30 \text{ V}, \text{ R}_L = 30 \Omega$ $I_{B1} = -I_{B2} = -33 \text{ mA}$	_	60	_	
	Storage time	t <sub>stg</sub>		_	250		ns
	Fall time	t <sub>f</sub>			90		

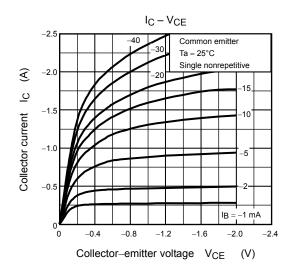
### Figure 3. Switching Time Test Circuit & Timing Chart

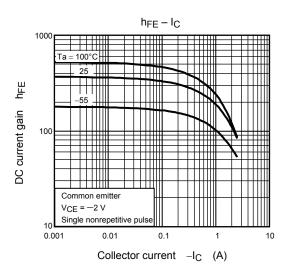


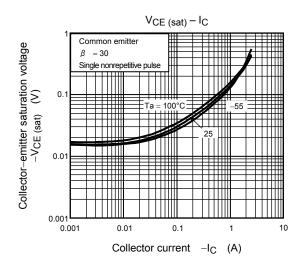
## Figure 2. Marking (Note 4)

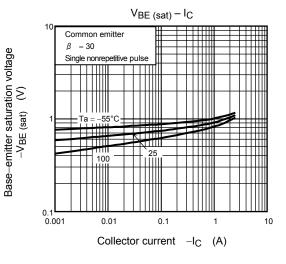


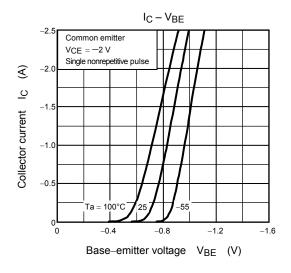
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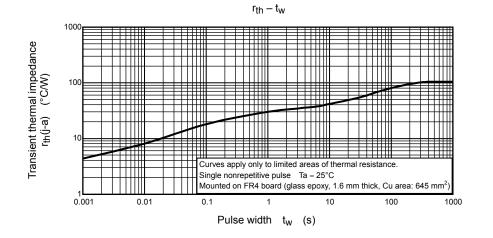


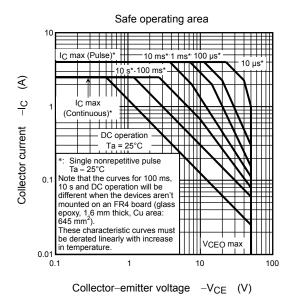












#### 2006-11-13

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